Appl. No. 10/659,737 Amdt. sent March 16, 2005 Amendment with Submission of Request for Request for Continued Examination [RCE] Under 37 CFR

Amendments to the Claims:

This listing of claims will replace all prior versions, and listings, of claims in the application:

Listing of Claims:

1	1. (Previously presented) A micro electromechanical systems (MEMS)
2	device comprising:
3	a scanning probe microscopy (SPM) component;
4	one or more fluidic channels formed in the SPM component;
5	one or more control valves to control a flow of fluid in the one or more fluidic
6	channels; and
7	one or more movable members formed in the SPM component, at least one fluidic
8	channel being formed in each movable member, wherein fluid flow through the at least one
9	fluidic channel produces movement in the movable member.
1 2	2. (Currently amended) A method for nanomachining using the a_MEMS device, the MEMs device comprising: of claim 1.
3	a scanning probe microscopy (SPM) component;
4	one or more fluidic channels formed in the SPM component;
5	one or more control valves to control a flow of fluid in the one or more fluidic
6	channels; and
7	one or more movable members formed in the SPM component, at least one fluidic
8	channel being formed in each movable member, wherein fluid flow through the at least one
9	fluidic channel produces movement in the movable member.
1	3. (Previously presented) A micro electromechanical systems (MEMS)
2	device comprising:
3	a scanning probe microscopy (SPM) component:

Appl. No. 10/659,737 Amdt. sent March 16, 2005 Amendment with Submission of Request for Request for Continued Examination [RCE] Under 37 CFR

4	at least one fluidic channel formed in the SPM component; and
5	a venturi tube formed along a portion of the fluidic channel,
6	wherein a vacuum can be developed by a flow of a gas or fluid through the
7	venturi tube.
1	4. (Currently amended) A micro electromechanical systems (MEMS) device
2	comprising:
3 .	a scanning probe microscopy (SPM) component;
4	one or more movable members formed in the SPM component;
5	a fluidic channel formed in a first movable member, the fluidic channel
6	configured to deliver fluid to a tip of the SPM component;
7	one or more control valves formed in the SPM component to control a flow of
8	fluid in the fluidic channel; and
9	an amount of an isotope disposed along the fluidic channel,
10	wherein the particles emitted by the isotope can be delivered by a fluid flowing in
11	the fluidic channel to the tip to affect the charge distribution in a region about the tip.
1	5. (Currently amended) A method for performing nanomachining on a
2	workpiece using the a MEMs device, the MEMs device comprising:
3	a scanning probe microscopy (SPM) component;
4	one or more movable members formed in the SPM component;
5	a fluidic channel formed in a first movable member, the fluidic channel
6	configured to deliver fluid to a tip of the SPM component;
.7	one or more control valves formed in the SPM component to control a flow of
8	fluid in the fluidic channel; and
9	an amount of an isotope disposed along the fluidic channel,

Appl. No. 10/659,737

Amdt. sent March 16, 2005

Amendment with Submission of Request for Request for Continued Examination [RCE] Under 37 CFR 1.114

wherein particles emitted by the isotope can be delivered by a fluid flowing in the
fluidic channel to the tip to affect charge distribution in a region about the tip, of claim 4 wherein
the particles are delivered to the tip.

6 - 7. (Canceled)

- 1 8. (Previously presented) The MEMS device as recited in claim 4 wherein 2 the isotope is Americium 241.
- 9. (Original) The MEMS device as recited in claim 4 wherein the amount of isotope is disposed in a single isotopic region on the SPM device, wherein the single isotopic region contains 1 microcurie or less of radioactivity.

10 - 25. (Canceled)

1 26. (Currently amended) A method of performing a nanomachining operation 2 comprising manipulating a device as recited in claim 4 relative to a surface, including 3 constraining motion of the device in a specific or constrained region,

a scanning probe microscopy (SPM) component;

the device comprising:

- one or more movable members formed in the SPM component;
- a fluidic channel formed in a first movable member, the fluidic channel
- 8 <u>configured to deliver fluid to a tip of the SPM component;</u>
- 9 <u>one or more control valves formed in the SPM component to control a</u>
- 10 <u>flow of fluid in the fluidic channel; and</u>
- an amount of an isotope disposed along the fluidic channel,
- wherein particles emitted by the isotope can be delivered by a fluid
- 13 flowing in the fluidic channel to the tip to affect charge distribution in a region about the
- 14 <u>tip</u>.

4

5

Appl. No. 10/659,737 Amdt. sent March 16, 2005 Amendment with Submission of Request for Request for Continued Examination [RCE] Under 37 CFR 1.114

1

2

3

1 2

3

- 1 27. (Previously presented) A method as in 26 in which the nanomachining 2 operation uses chemical or biological chips or devices in which material therefore is placed in 3 wells in a regular arrangement on a plane or surface(s).
 - 28. (Previously presented) A method as in 27 in which the material is DNA which has been marked optically, electrically or chemically so as to interact with optical, electrical or chemical detectors or emitters associated with or integrated in the device.

29. - 37. (Canceled)

38. ((Previously presented)) The MEMS device of claim 1 further comprising a cantilever formed in the SPM component and operatively coupled to the moveable members, wherein movement in the movable members serves to move the cantilever.

39 - 40. (Canceled)

- 1 41. (Previously presented) The MEMS device of claim 4 wherein the fluid
 2 flow comprises one of moving fluid from the fluidic channel formed in the first moveable
 3 member to create at least a partial vacuum thereby effecting movement of the first moveable
 4 member and moving fluid into the fluidic channel formed in the first moveable member wherein
 5 a force of the fluid effects movement of the first moveable member.
- 1 42. (Previously presented) The MEMS device of claim 4 wherein fluid flow through the at least one fluidic channel produces movement in the first movable member.
- 1 43. (Previously presented) The MEMS device of claim 42 further comprising 2 a cantilever formed in the SPM component and operatively coupled to the moveable members, 3 wherein a fluidic channel is formed in each moveable member, wherein movement in the 4 movable members serves to move the cantilever.

Appl. No. 10/659,737 Amdt. sent March 16, 2005 Amendment with Submission of Request for Request for Continued Examination [RCE] Under 37 CFR 1.114

l	44. (Previously presented) The MEMS device as recited in claim 4 wherein
2	the moveable members act as passive elements.
1	45. (Previously presented) The MEMS device as recited in claim 4 wherein
2	the moveable members produce electrical signals during movement, wherein the electrical
3	signals serve to control subsequent movements.
1	46. (Previously presented) The MEMS device as recited in claim 45 wherein
2	the electrical signals serve to obtain one of a predetermined motion of a first moveable member,
3	a predetermined displacement of the first moveable member, a zero displacement position of the
4	first moveable member.
1	47. (Previously presented) The MEMS device as recited in claim 4 further
2	comprising a circuit for monitoring changes in charge accumulation in the fluidic channel as the
3	isotope is moved by fluid flow.
1	48. (Currently amended) A method for nanoelectric discharge machining
2	using the a MEMS device as recited in claim 4, the method comprising imaging a surface to be
3	machined and measuring surface features of the surface to be machined, the imaging and
4	measuring being performed using a scanning probe microscopy technique
5	the MEMs device comprising:
6	a scanning probe microscopy (SPM) component;
7	one or more movable members formed in the SPM component;
8	a fluidic channel formed in a first movable member, the fluidic channel
9	configured to deliver fluid to a tip of the SPM component;
10	one or more control valves formed in the SPM component to control a
11	flow of fluid in the fluidic channel; and
12	an amount of an isotope disposed along the fluidic channel,

Appl. No. 10/659,737 Amdt. sent March 16, 2005 Amendment with Submission of Request for Request for Continued Examination [RCE] Under 37 CFR 1.114

13	wherein particles emitted by the isotope can be delivered by a fluid
14	flowing in the fluidic channel to the tip to affect charge distribution in a region about the
15	tip.
	49 - 58. (Canceled)
1	59. (Previously presented) A micro electromechanical systems (MEMS)
2	device comprising:
3	a scanning probe microscopy (SPM) component;
4	a fluidic channel formed in the SPM component, the fluidic channel configured to
5	deliver fluid to a tip of the SPM component;
6	an amount of an isotope disposed along the fluidic channel, wherein the particles
7	emitted by the isotope can be delivered by a fluid flowing in the fluidic channel to the tip to
8	affect the charge distribution in a region about the tip; and
9	a circuit for monitoring changes in charge accumulation in the fluidic channel as
10	the isotope is moved by a flow of fluid.